

# Coupling of STM with Hard X-ray $\mu$ -Beam from 27m Long Undulator at SPring-8

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## **Collaborators**

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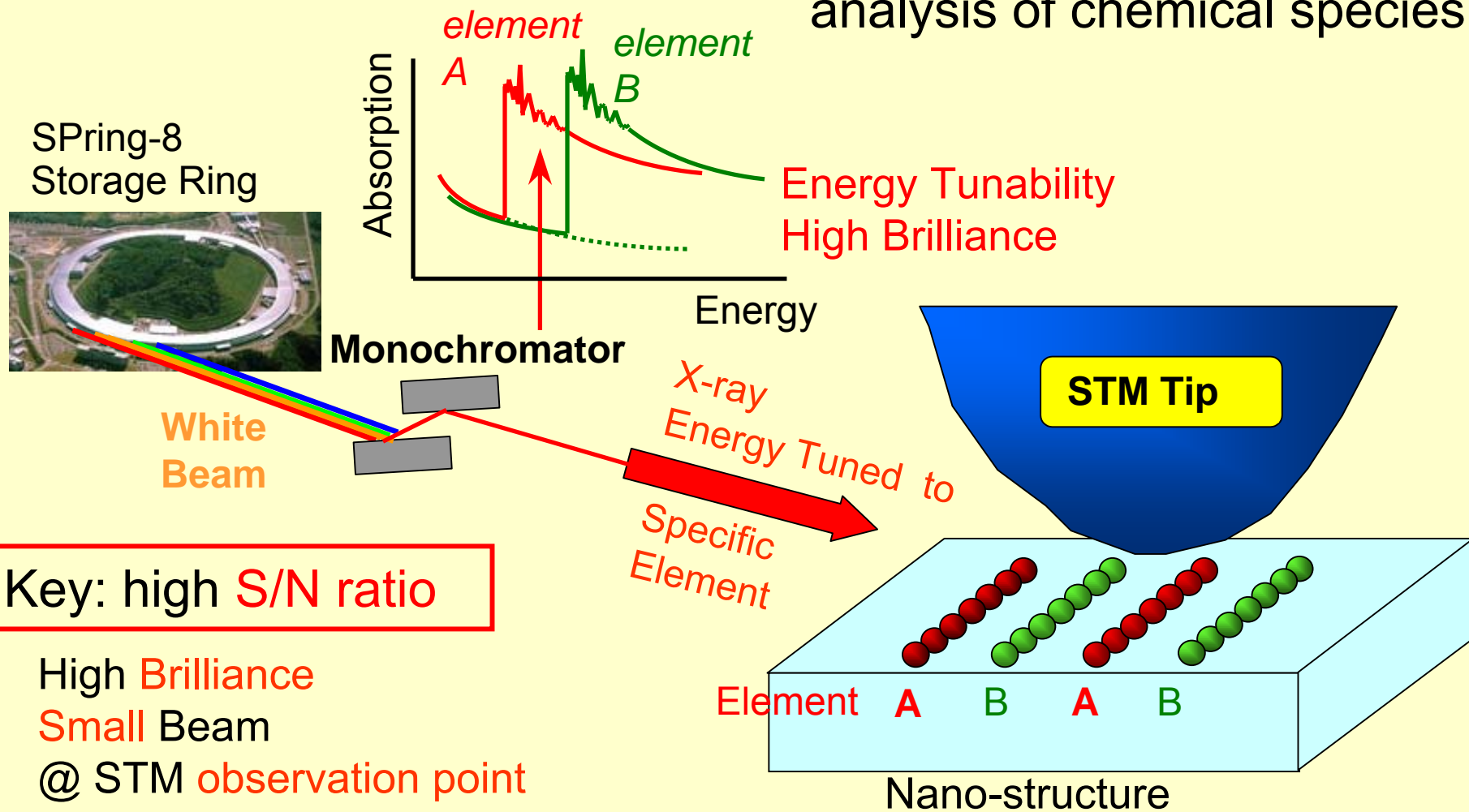
K. Kitamoto, Y. Takagi, Y. Tanaka, D. Miwa, M. Yabashi, M. Ishii,  
S. Shin, T. Ishikawa

# Concept of SR (Synchrotron Radiation)-STM

STM + Inner-Shell Excitation by SR

STM +

analysis of chemical species



Key: high S/N ratio

High Brilliance

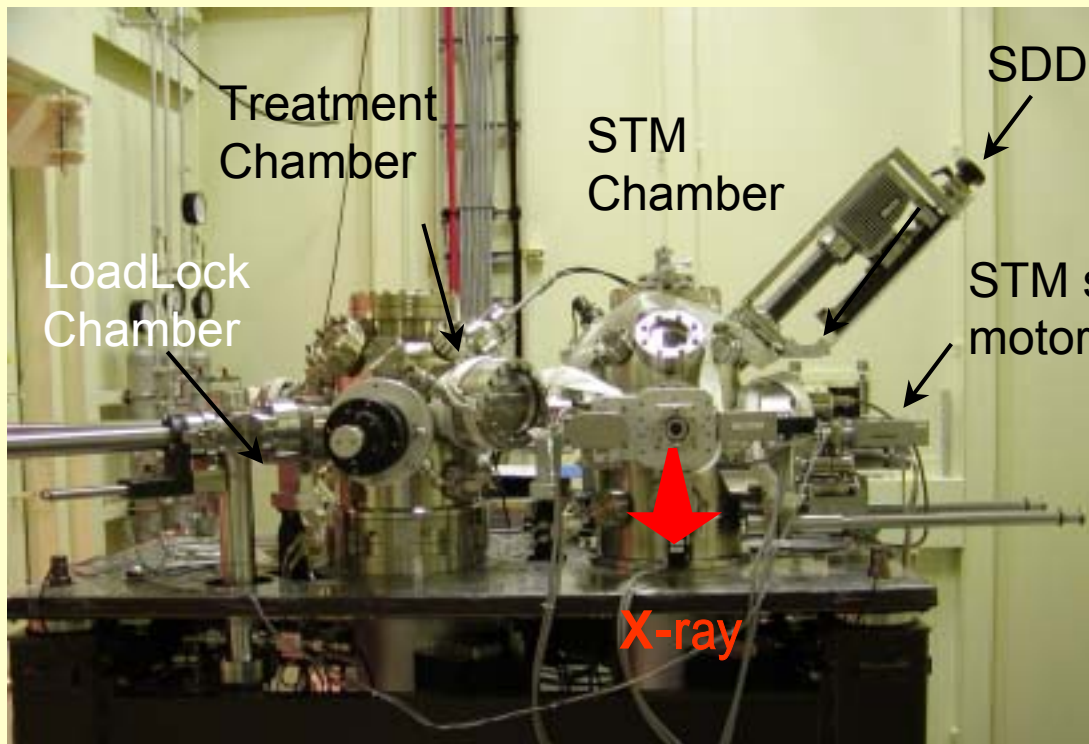
Small Beam

@ STM observation point

fast alignment, in UHV

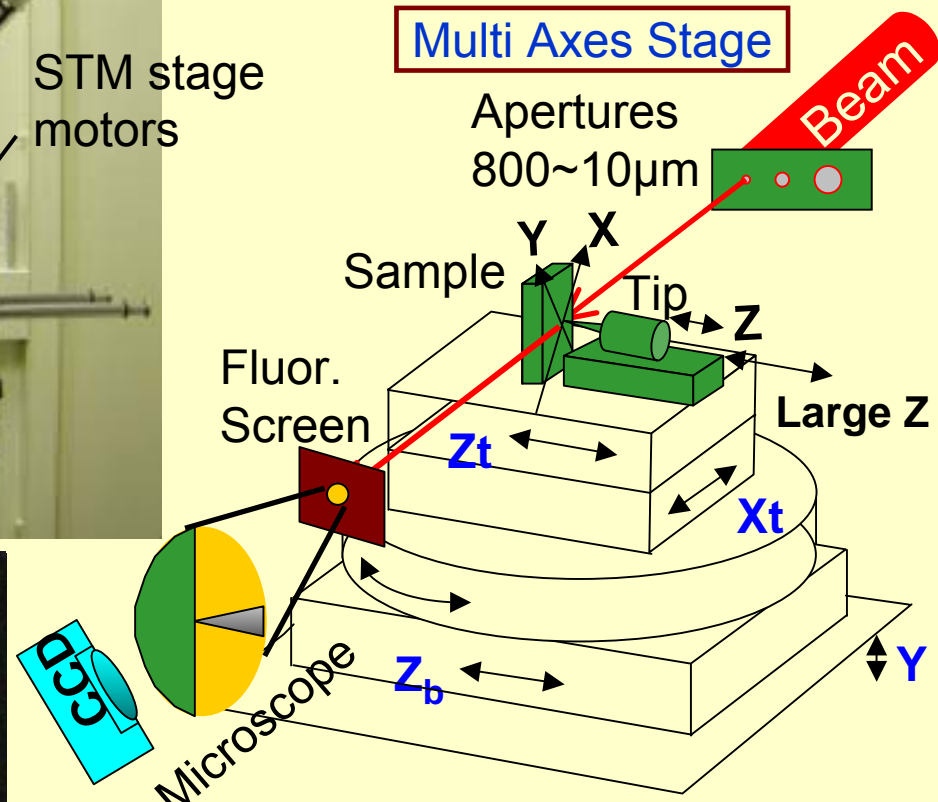
# UHV Chamber @BL19LXU, SPring-8

A.Saito et al. : J.of Synchrotron Rad. (2006), in press.

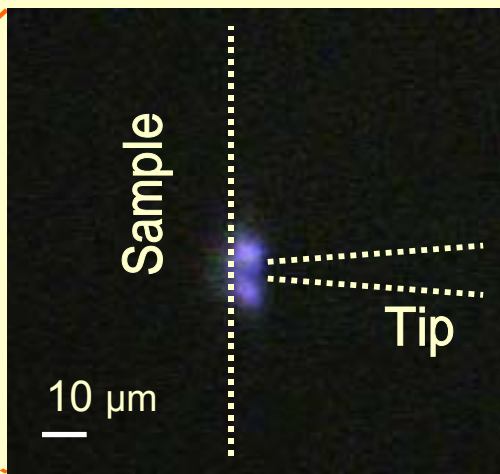
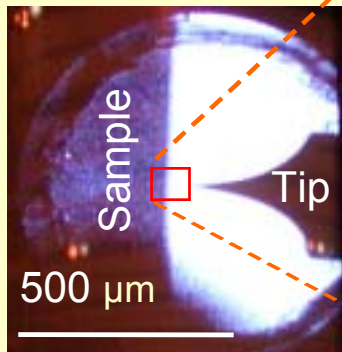


Fluorescence Monitor  
Adsorbate } check  
Tip Align

Multi Axes Stage



Coarse align



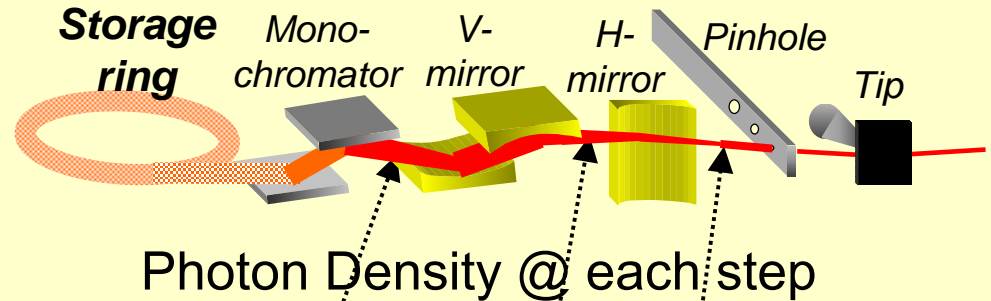
Position Monitor  
Silhouette  
Real-time monitor

Accuracy of ~1 $\mu$ m  
Fast Align  
(as diffraction exp.)

# Light Source

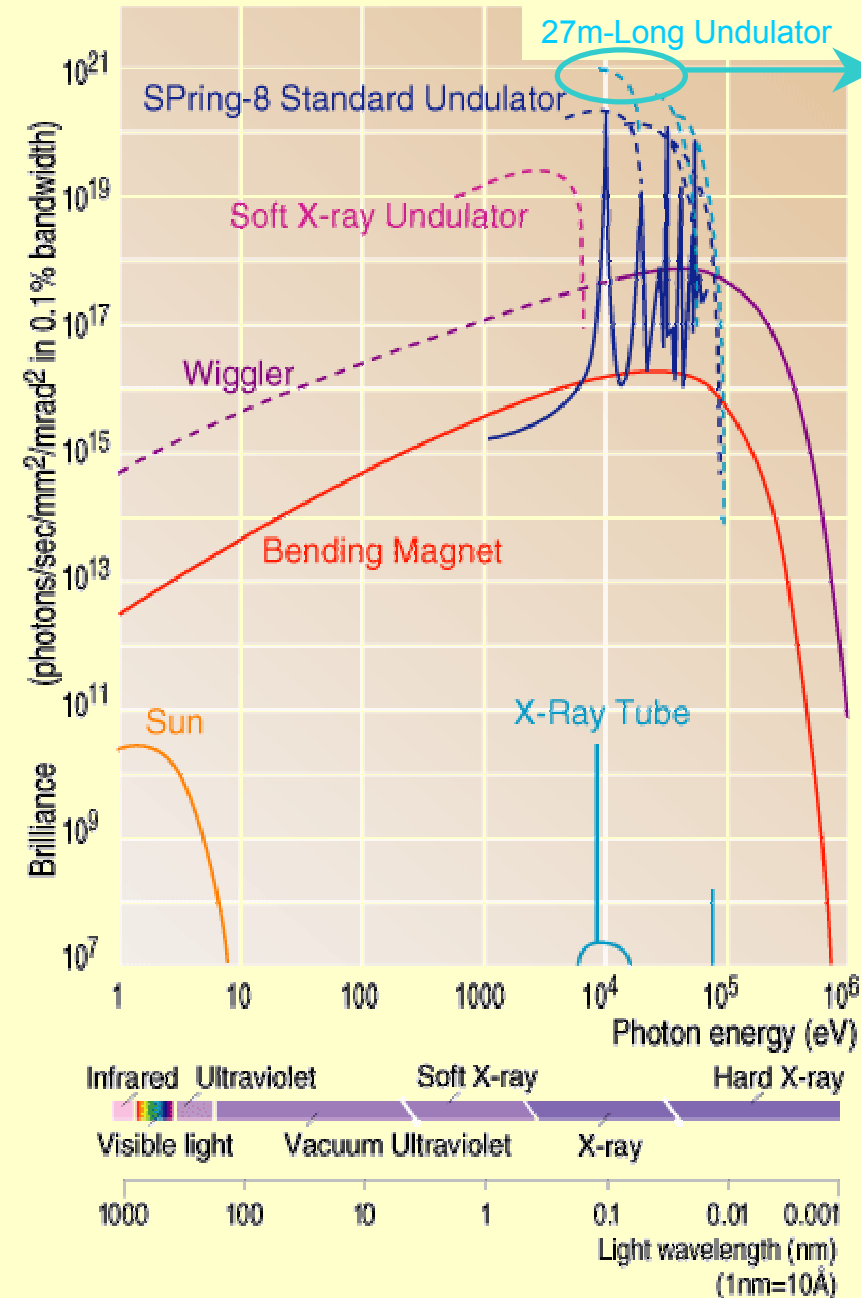
**BL19LXU**

Brilliance:  $\sim 1 \times 10^{21}$  (photons/s /mrad<sup>2</sup>/mm<sup>2</sup>/0.1% b.w./100mA)  
 Energy range: 7.2~18(keV)



From Upstream	Only with Mono	Vertical Focus	Horizontal Focus	After Pin-hole
Beam Shape				
Beam Size (@ sample)	1000 x 500 (H x V μm)	1000 x 200	50 x 200	10 x 10
Photon density (@ sample)	$4 \times 10^{14}$	$1 \times 10^{15}$	$1 \times 10^{16}$	$1 \times 10^{16}$

(photons/s/mm<sup>2</sup>/0.1% b.w./100mA)



# How the irradiation affects to STM observation ?

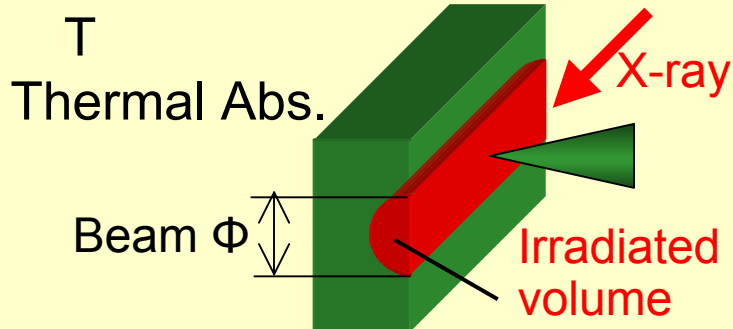
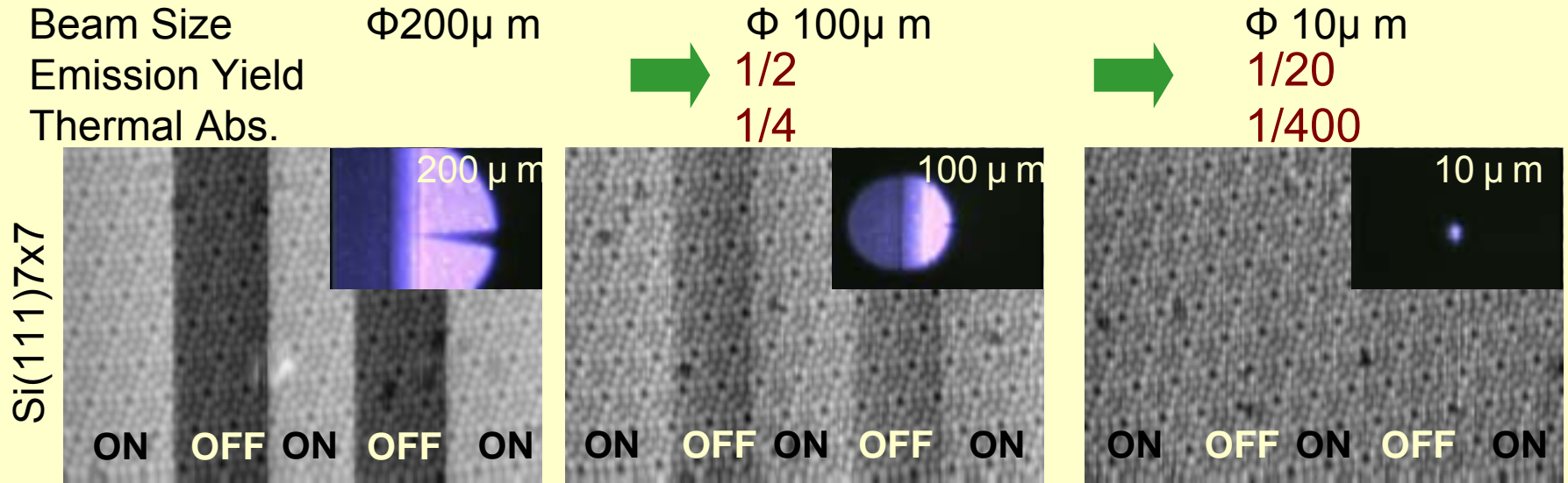
In-situ observation w/atomic resolution is possible @ BL19

Beam On/Off → Bright & Dark Contrast

$V_s = -2V$ ,  $I_t = 0.3nA$  (Const. Current mode = contrast is based on Tip motion)

Reduction of the contrast (noise)

(Incident Energy 16.5 keV, angle 1.5 °)



Contrast is dominated by Thermal Expansion

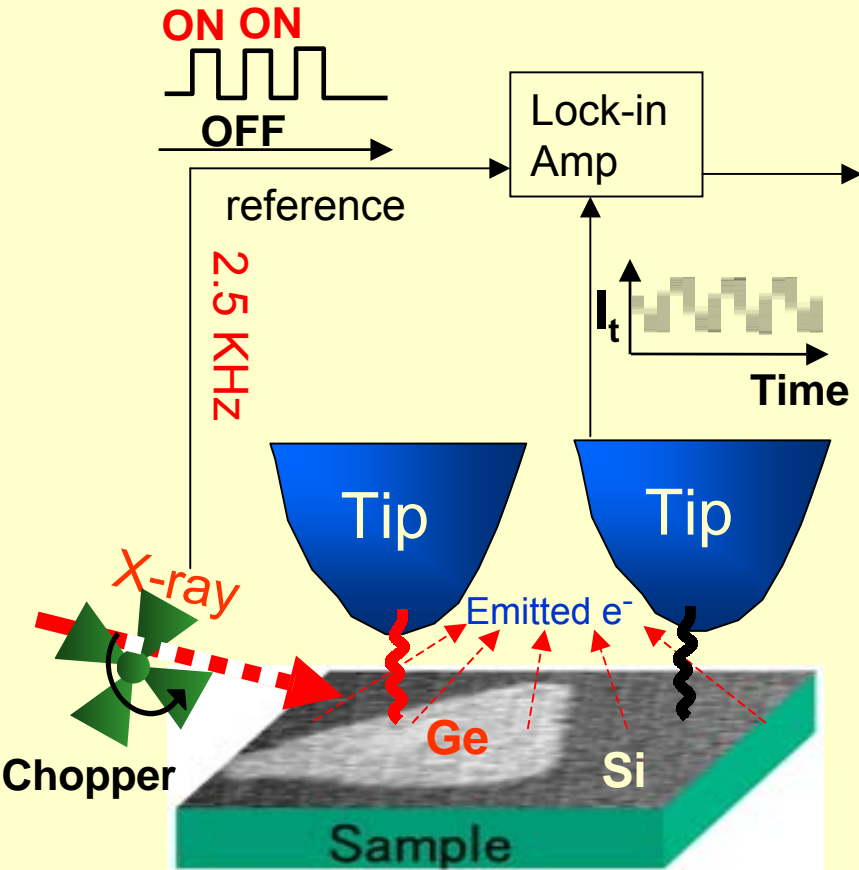
- Reduction of the Beam size to  $\Phi 10\mu m$ , → the contrast was removed effectively.
- For higher S/N ratio with Focus Beam, → total reflection condition is important.

# Elemental Analysis - Mode 1. Point spectra

## Tip=fixed, Energy=scanned

A.Saito et al. : JJAP(2006), in press

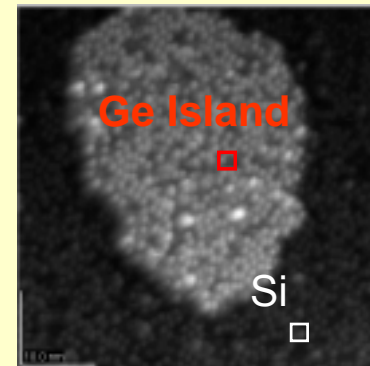
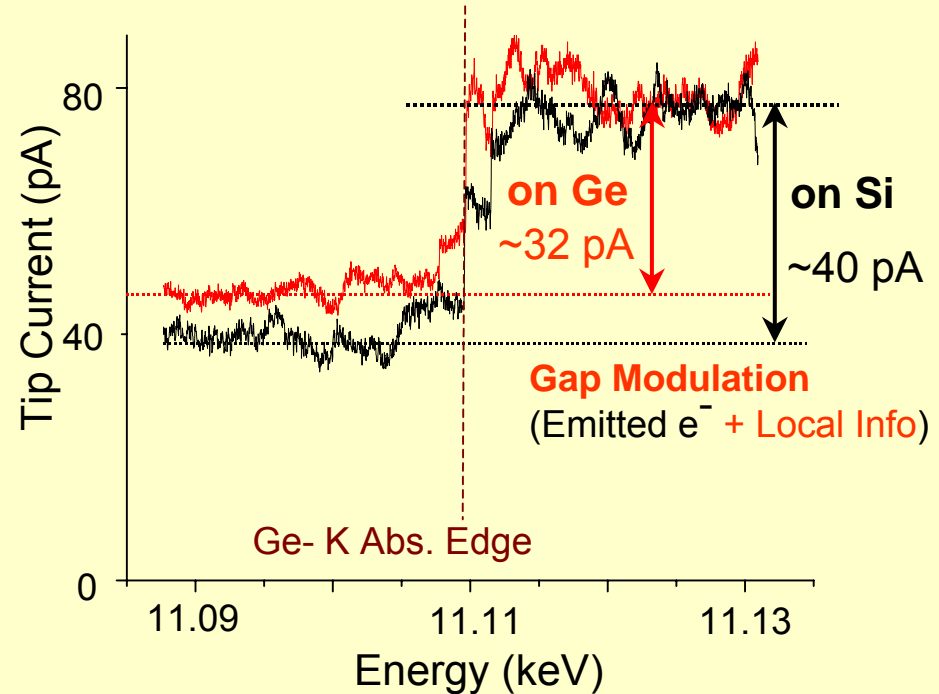
A.Saito et al. : J.of Synchrotron Rad. (2006), in press.



### Tunneling Condition

(Tip Current =

Emitted  $e^-$  + Tunneling Current)



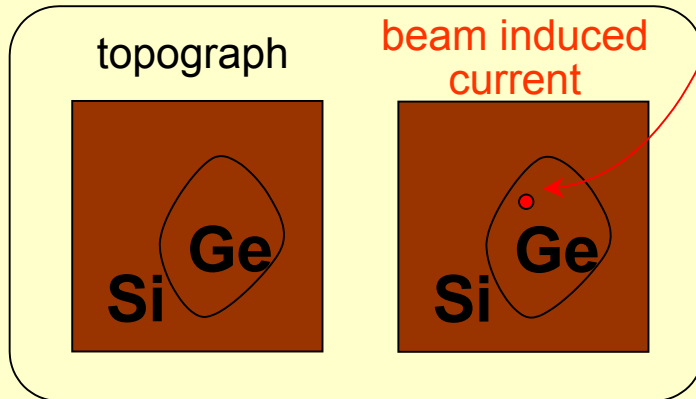
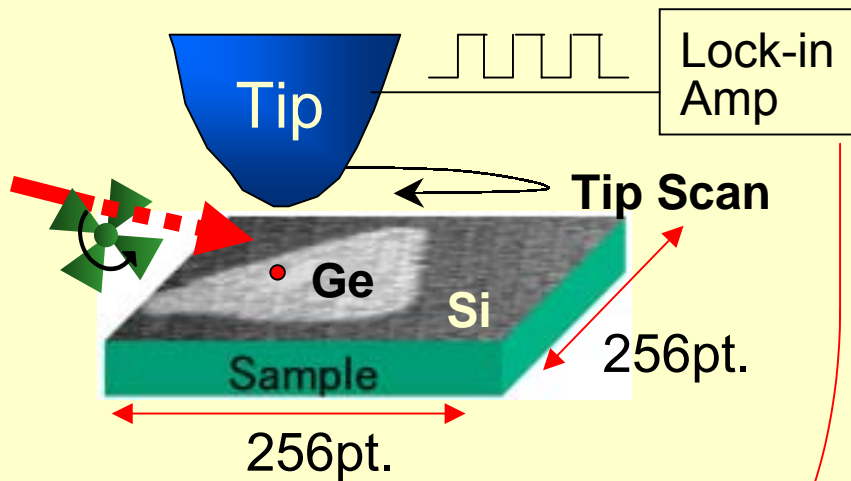
35x35nm,  
 $V_s = -2.0V$ ,  $I_t = 0.3nA$

Ge nanoisland on  
Si(111)

# Elemental Analysis - Mode 2. imaging

**Tip= scanned, Energy= fixed**

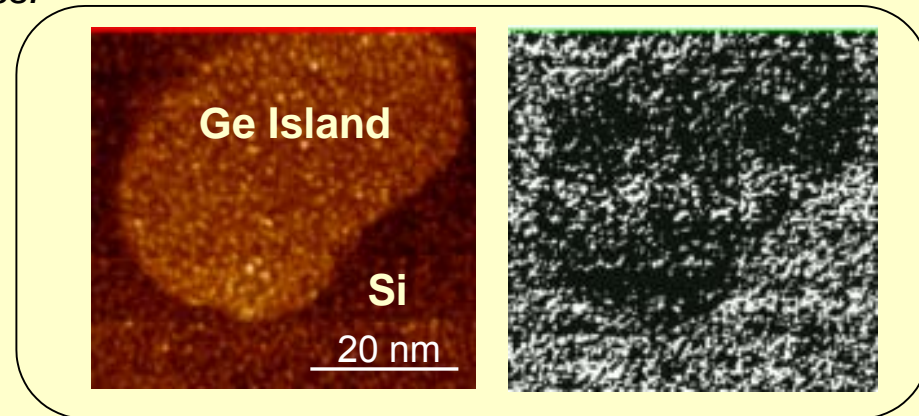
A.Saito et al. : J.of Synchrotron Rad. (2006), in press.



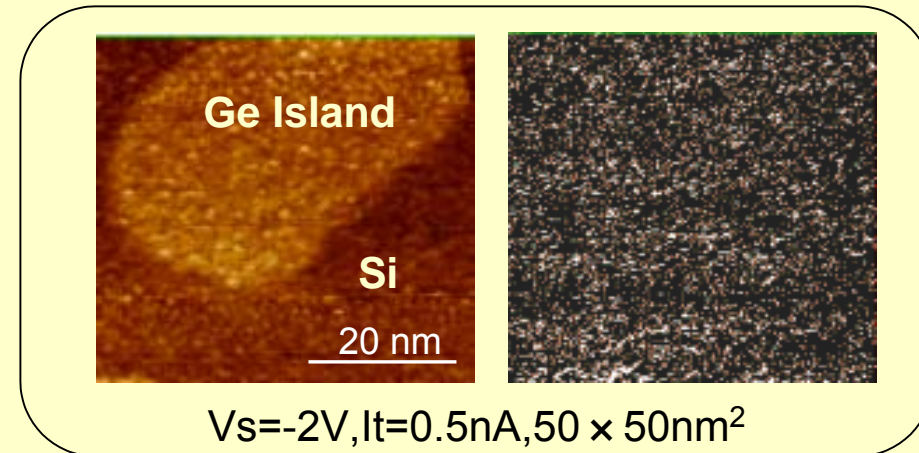
Topograph

Beam Induced Image

11.114keV



11.090keV



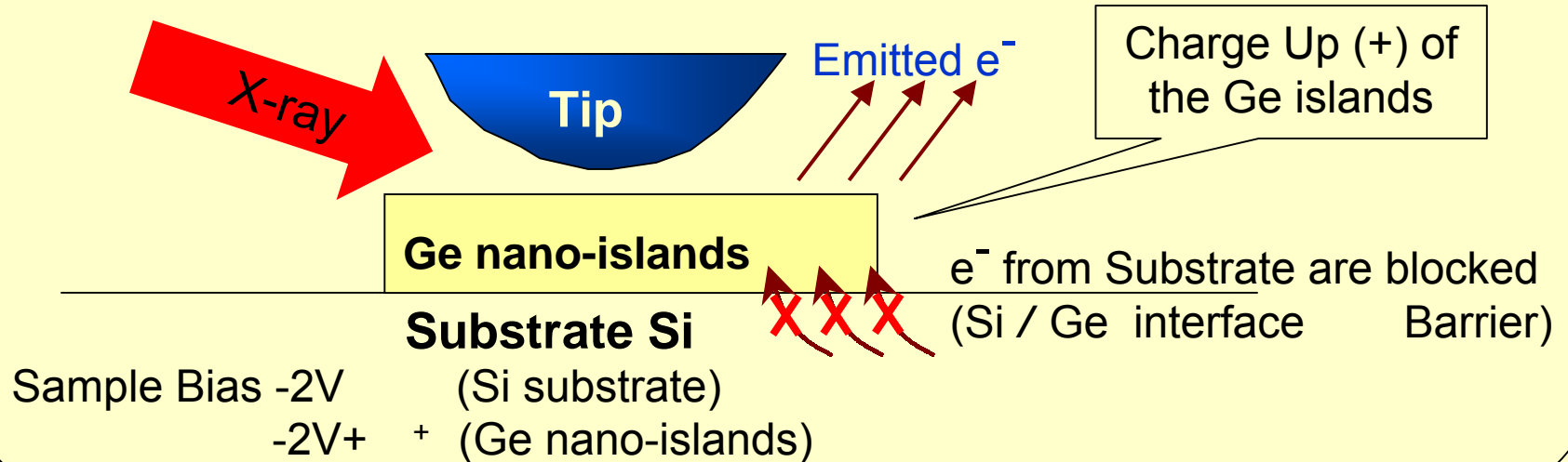
One-point spectra (previous page)

agreement

Ge nano-islands look dark only for the Tip Current Image @ higher energy.

# Possible Origin of the Feature

## Charge Up of Ge islands followed by emission of electrons



## Conclusion

- Specific change of the Tunneling signal between the **Ge nano-islands** and the **surrounding Si surface** was observed across the Ge absorption edge. Spatial resolution is  $< \sim 10$  nm.
- Independently obtained data (**One-point Spectra** & **Tip-Current Image**) were in good agreement with each other. c.f. Reproducibility was confirmed
- The phenomenon cannot be explained by emitted electrons.